

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO
MI22-1171

SERIAL NO

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Salman Akram et al.

FILING DATE

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U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
GJM	AA	5,750,435	05/12/98	Pan			
	AB	5,716,875	02/10/98	Jones, Jr. et al.			
	AC	5,714,788	02/03/98	Ngaoaram			
	AD	5,705,409	01/06/98	Witek			
	AE	5,672,525	09/30/97	Pan			
	AF	5,599,726	02/04/97	Pan			
	AG	5,571,734	11/05/96	Tseng et al.			
	AH	5,382,533	01/17/95	Ahmad et al.			
	AI	5,225,355	07/06/93	Sugino et al.			
GJM	AJ	3,933,530	01/20/76	Mueller et al.			
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
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	AL							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

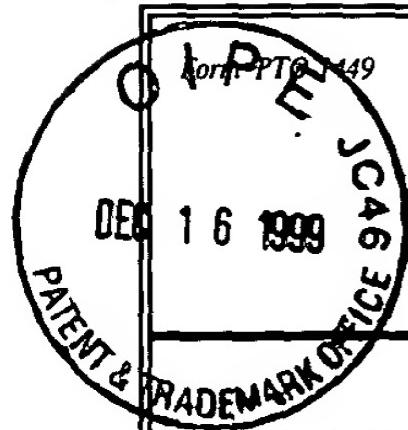
GJM	AR	Improvement of SiO ₂ /Si Interface Properties by Fluorine Implantation, K. Ohyu, Y. Nishioka, Y. Ohji, and					
		Natsuaki, International Conference on Solid State Devices and Materials, 1988, pp. 607-608.					
GJM	AS	The Effect of Fluorine on Gate Dielectric Properites, P.J. Wright, M. Wong and K.C. Saraswat, IEEE 1987,					
		pp. 574-577.					
	AT						

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MI22-1171SERIAL NO.
09/292,132LIST OF ART CITED BY APPLICANT
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
SA	AA	5,672,544	9/30/97	Pan	437	200	
	AB	5,369,297	11/29/94	Kusunoki et al.	257	344	
SA	AC	5,814,863	9/29/98	Pan	257	344	
	AD						
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FOREIGN PATENT DOCUMENTS

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